ON Semiconductor

PRODUCT BULLETIN # 16862

Generic Copy

Issue Date: 24-May-2012

TITLE: SOIC-7/8, 14, 16 Lead Conversions from MSL3 to MSL1

PROPOSED FIRST SHIP DATE: 24-May-2012

AFFECTED CHANGE CATEGORY(S): Assembly Process Moisture Sensitivity Level (MSL)

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:
Contact your local ON Semiconductor sales office or <Scott.Brow@onsemi.com>

NOTIFICATION TYPE:
ON Semiconductor considers this change approved unless specific conditions of acceptance are provided in writing. To do so, contact <quality@onsemi.com>.

DESCRIPTION AND PURPOSE:

Through continuous process improvement of our SOIC assembly line, ON Semiconductor would like to announce that it will be changing the Moisture Sensitivity Level for those products listed in this Product Bulletin from MSL3 to MSL1. This means that the product listed in this product bulletin will no longer be shipped in dry packing materials. There has been no change in the BOM material set to achieve this higher MSL rating, only improvements to the assembly process.

RELIABILITY DATA SUMMARY:

Reliability was performed to confirm the improvement with the results summarized here:

NCP1271D65R2G

#	Test	Test Conditions	Read Points	Sample Size	Results
1	TC-PC	-65C to +150C	Test @ 1008cycles	1 lot x 80 units	0/80
2	UHAST-PC	TA=130C, RH=85%, PSI=18.8, no Bias	Test @ 1008hrs	1 lot x 80 units	0/80
3	HAST-PC	TA=130C, RH=85%, PSI=18.8, Bias	Test @ 1008hrs	1 lot x 80 units	0/80
4	SAT-PC	Post MSL1 260C	Pre and Post PC	1 lot x 80 units	0/5

NCP1396DR2G

#	Test	Test Conditions	Read Points	Sample Size	Results
1	TC-PC	-65C to +150C	Test @ 1008cycles	1 lot x 80 units	0/80
2	UHAST-PC	TA=130C, RH=85%, PSI=18.8, no Bias	Test @ 1008hrs	1 lot x 80 units	0/80
3	HAST-PC	TA=130C, RH=85%, PSI=18.8, Bias	Test @ 1008hrs	1 lot x 80 units	0/80
4	SAT-PC	Post MSL1 260C	Pre and Post PC	1 lot x 80 units	0/5

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SCY99124DR2G

#	Test	Test Conditions	Read Points	Sample Size	Results
1	TC-PC	-65C to +150C	Test @ 1008cycles	1 lot x 80 units	0/240
2	UHAST-PC	TA=130C, RH=85%, PSI=18.8, no Bias	Test @ 1008hrs	1 lot x 80 units	0/240
3	SAT-PC	Post MSL1 260C	Pre and Post PC	1 lot x 80 units	0/15

NCP1606ADR2G

#	Test	Test Conditions	Read Points	Sample Size	Results
1	TC-PC	-65C to +150C	Test @ 1008cycles	3 lots x 80 units	0/240
2	AC-PC	TA=121C, RH=100%, PSI=15	Test @ 96 hrs	3 lots x 80 units	0/240
3	UHAST-PC	TA=130C, RH=85%, PSI=18.8, no Bias	Test @ 1008hrs	3 lots x 80 units	0/240
4	SAT-PC	Post MSL1 260C	Pre and Post PC	3 lots x 5 units	0/15

NCP1654BD65R2G

#	Test	Test Conditions	Read Points	Sample Size	Results
1	TC-PC	-65C to +150C	Test @ 500 cycles	1 lot x 80 units	0/80
2	UHAST-PC	TA=130C, RH=85%, PSI=18.8, no Bias	Test @ 1008hrs	1 lot x 80 units	0/80
3	SAT-PC	Post MSL1 260C	Pre and Post PC	1 lot x 5 units	0/5

NCP1652DR2G

#	Test	Test Conditions	Read Points	Sample Size	Results
1	TC-PC	-65C to +150C	Test @ 1008cycles	1 lot x 77 units	0/77
2	AC-PC	TA=121C, RH=100%, PSI=15	Test @ 96 hrs	1 lot x 77 units	0/77
3	UHAST-PC	TA=130C, RH=85%, PSI=18.8, no Bias	Test @ 1008hrs	1 lot x 77 units	0/77
4	SAT-PC	Post MSL1 260C	Pre and Post PC	1 lot x 5 units	0/5

NCP1928DR2G

#	Test	Test Conditions	Read Points	Sample Size	Results
1	TC-PC	-65C to +150C	Test @ 500 cycles	1 lot x 80 units	0/80
2	SAT-PC	Post MSL1 260C	Pre and Post PC	1 lot x 5 units	0/5

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List of affected General Parts:

NCL30001DR2G	NCP1238BD65R2G	NCP1396BDR2G
NCP1218AD65R2G	NCP1252ADR2G	NCP1397ADR2G
NCP1219AD100R2G	NCP1252BDR2G	NCP1397BDR2G
NCP1219AD65R2G	NCP1252CDR2G	NCP1562ADR2G
NCP1219BD100R2G	NCP1271D100R2G	NCP1562BDR2G
NCP1219BD65R2G	NCP1271D65R2G	NCP1631DR2G
NCP1234AD65R2G	NCP1288BD65R2G	NCP1652ADR2G
NCP1234BD100R2G	NCP1379DR2G	NCP1652DR2G
NCP1234BD65R2G	NCP1380ADR2G	NCP1927DR2G
NCP1236AD100R2G	NCP1380BDR2G	NCP4303ADR2G
NCP1236AD65R2G	NCP1380CDR2G	NCP4303BDR2G
NCP1236BD100R2G	NCP1380DDR2G	NCP5104DR2G
NCP1236BD65R2G	NCP1392BDR2G	NCP5106ADR2G
NCP1237AD65R2G	NCP1393BDR2G	NCP5106BDR2G
NCP1237BD65R2G	NCP1396ADR2G	NCP5111DR2G
NCP1238AD65R2G		NCP5304DR2G